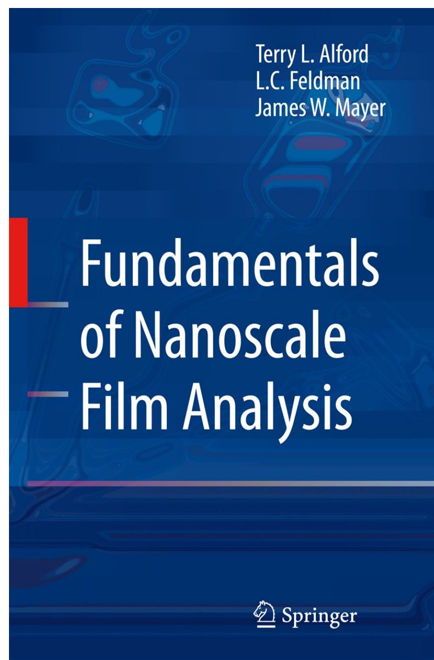

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Materials Science : Characterization and Evaluation of Materials

Alford, T.L., Feldman, L.C., Mayer, J.W., Arizona State University Dept. Chemical & Materials, Tempe, AZ, USA

Fundamentals of Nanoscale Film Analysis

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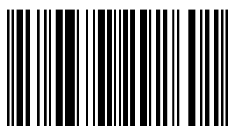

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